

<b>Notice of References Cited</b>	Application/Control No. 10/585,690		Applicant(s)/Patent Under Reexamination HEMMING ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,179,685 A	12-1979	O'Maley, James B.	382/135
*	B	US-4,365,700 A	12-1982	Arimoto et al.	194/206
*	C	US-4,511,794 A	04-1985	Imamichi, Tutomu	235/379
*	D	US-4,552,350 A	11-1985	Nagy et al.	271/3.19
*	E	US-4,736,852 A	04-1988	Edin et al.	209/534
*	F	US-4,745,266 A	05-1988	Miura, Yoshifumi	235/379
*	G	US-4,744,468 A	05-1988	Goi et al.	209/534
*	H	US-4,775,783 A	10-1988	Sasaki et al.	235/379
*	I	US-4,988,849 A	01-1991	Sasaki et al.	235/379
*	J	US-5,076,441 A	12-1991	Gerlier, Andre	209/534
*	K	US-5,071,031 A	12-1991	Yuge et al.	221/3
*	L	US-5,335,484 A	08-1994	Hain, David A.	53/582
*	M	US-5,436,435 A	07-1995	McMillan, David J.	235/379

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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#### NON-PATENT DOCUMENTS

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	U	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,719,383 A	02-1998	Forrest, Simon J.	235/379
*	B	US-6,006,989 A	12-1999	Ademmer et al.	235/379
*	C	US-6,131,809 A	10-2000	Drescher et al.	235/379
*	D	US-2002/0092905 A1	07-2002	Katou et al.	235/379
*	E	US-6,422,458 B1	07-2002	Katou et al.	235/379
*	F	US-2002/0121422 A1	09-2002	Shibata et al.	194/206
*	G	US-2002/0153291 A1	10-2002	Otsuka, Toru	209/534
*	H	US-2002/0153290 A1	10-2002	Otsuka, Toru	209/534
*	I	US-2002/0173874 A1	11-2002	Lax, Jacob	700/223
*	J	US-2002/0185531 A1	12-2002	Matzig, Christoph	235/382
*	K	US-2003/0121077 A1	06-2003	Katou et al.	902/12
*	L	US-6,640,156 B1	10-2003	Brooks et al.	700/213
*	M	US-6,659,258 B2	12-2003	Otsuka, Toru	194/206

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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	X	

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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0164147 A1	08-2004	Jenkins et al.	235/382
*	B	US-2004/0172730 A1	09-2004	Washington et al.	902/006
*	C	US-2005/0263582 A1	12-2005	Yokoi et al.	235/379
*	D	US-2007/0221469 A1	09-2007	Katou et al.	194/206
*	E	US-2007/0205260 A1	09-2007	Tennant, Alan	235/379
*	F	US-7,407,090 B2	08-2008	Jantsch, Gregory	235/379
*	G	US-2008/0283450 A1	11-2008	Hemming et al.	209/534
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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